

INFORMATION DISCLOSURE CITATION IN AN APPLICATION						ATTY. DOCKET NO. <b>50212-527</b>		SERIAL NO.			
(PTO-1449)						APPLICANT <b>Hitoshi HATAYAMA, et al.</b>					
						FILING DATE <b>September 05, 2003</b>		GROUP			
U.S. PATENT DOCUMENTS											
EXAMINER'S INITIALS		CITE NO.	Document Number Number-Kind Code <sub>2</sub> (if known)		Publication Date MM-DD-YYYY		Name of Patentee or Applicant of Cited Document		Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
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FOREIGN PATENT DOCUMENTS											
EXAMINER'S INITIALS		CITE NO.	Foreign Patent Document Country Codes -Number + -Kind Codes (if known)		Publication Date MM-DD-YYYY		Name of Patentee or Applicant of Cited Document		Pages, Columns, Lines Where Relevant Figures Appear	Translation	
										Yes	No
mmd			JP WO 01/05005 A1		01/18/2001		SUMITOMO ELECTRIC INDUSTRIES, LTD.			(Japan w/English Abstract)	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)											
EXAMINER'S INITIALS		CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.								
mmd			K. Inoue, et al., "Tunable Gain Equalization Using a Mach-Zehnder Optical Filter in Multistage Fiber Amplifiers," IEEE Photonics Technology Letters, Vol. 3, No. 8, pp.718-720 (1991)								
mmd			H. Toba, et al., "Demonstration of Optical FDM Based Self-Healing Ring Network Employing Arrayed-Waveguide-Grating ADM Filters and EDFAs," Proceedings of ECOC '94, pp.263-266 (1994)								
mmd			M. Fukutoku, et al., "OAA1998, Tech. Dig. FA4								
EXAMINER Mark Hellner											
DATE CONSIDERED 8/18/2005											

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